

Transaction Information

Tool ID	ETS453
Tool Status	Disconnected
Location	Dresden, Germany
Wafer Size	300 mm
Fab Section	Test
Tool Available Date	2021-10-04

General Product Information

Vendor Supplier	CRENCE
Model	SAPPHIRE
Vintage	2008
Serial No	70421
Asset Description	Wafer Tester
Software Version	LTX Credence customized for AMD/ Globalfoundries
CIM	n/a
Process	Wafer Test

Hardware Configuration (Fab)

System Type	Description	Quantity	Status
Main System	Tester	1	
Handler System	NONE	0	OK
Factory Interface	NONE	0	OK
Options System	Adapter for TEL P12XIn+	1	OK
Others	n/a	0	OK

Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
cold idled LTX CREDESCENCE Sapphire Tester	1	

Missing/Faulty Parts / Accesories List

Description	Quantity
channel boards and DPS units defect	5

Tool Pictures

General

Tool Reference







General

Tool Reference



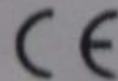
Manufacture Serial

S/N Tool Plate



credence

PRODUCT: SAPPHIRE
MODEL: ENHANCED POWER
S/N: SAPPE-R70421



MFG DATE: March 29, 2008

XTOS™ Sequencer Per Pin® Keep Alive®

THIS PRODUCT IS COVERED BY ONE OR MORE OF THE FOLLOWING

US PATENTS AND THEIR FOREIGN EQUIVALENTS

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Manufactured in

334-8431-01

Additional Configuration Files